

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application.
(No claims are amended.)

Listing of Claims:

Claims 1-24 (Canceled)

Claim 25 (Previously presented): A probe card made by a method comprising:
receiving at a computer over a network from a prospective customer information
describing a wafer to be tested;
generating from said information a verification package comprising a proposed design of
a probe card for testing said wafer; and
communicating over said network with said prospective customer regarding acceptability
of said proposed probe card design.

Claim 26 (Previously presented): The probe card of Claim 25, further comprising providing a
graphical interface for use by said prospective customer to enable input of said information
describing a wafer to be tested.

Claim 27 (Previously presented): The probe card of Claim 26, wherein said graphical interface
comprises at least one Web page.

Claim 28 (Previously presented): The probe card of Claim 25, further comprising accepting an
order from said prospective customer to manufacture said proposed probe card design.

Claim 29 (Previously presented): The probe card of Claim 25, further comprising verifying said
proposed probe card design.

Claim 30 (Previously presented): The probe card of Claim 25, wherein said verification
package further comprises drawings of said proposed probe card design.

Claim 31 (Previously presented): The probe card of Claim 25, wherein said communicating step further comprises notifying said prospective customer of proposed modifications to said proposed probe card design.

Claim 32 (Previously presented): The probe card of Claim 29, wherein said verifying step further comprises simulating operation of said proposed probe card design.

Claim 33 (Previously presented): The probe card of Claim 29, wherein said verifying step further comprises performing an automated simulation of said proposed probe card design.

Claim 34 (Previously presented): The probe card of Claim 29, wherein said verifying step further comprises performing a simulation based on particular specifications designated by said prospective customer.

Claim 35 (Previously presented): The probe card of claim 25 further comprising fabricating a probe card from said proposed probe card design.